

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/007,300	<b>Applicant(s)/Patent under Reexamination</b>  JONO ET AL.
	<b>Examiner</b>  Thien F. Tran	<b>Art Unit</b>  2811

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
257	374	1/7/2005	TT
257	396-400	1/7/2005	TT
257	510,519	1/7/2005	TT
257/647-648		1/7/2005	TT